

## Prober Sunlab sheet resistance scanner

**Short description :** Sunlab Sherescan High resolution (selective) emitter sheet resistance mapping.

**Features :**

**Measurement range :** 10-200 Ohms/sq

Wafer dimensions & shapes : max 210mm, thickness 100-1000  $\mu\text{m}$ , square, semi square, round

Four point probe : Jandel cylindrical probe head, pin spacing 0,635 mm, load(per needle) 100g, needle radius 100 $\mu\text{m}$

Wafer fixation : vacuum

**Localisation :** ESD BENCH 9

**Personne(s) ressource(s) :** Benoit Hubert, Pascal Simon,

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